SHEET 1 OF

ATTY DOCKET NO. SERIAL NO. Form PTO 1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE (Modified) 10/085,734 **APPLICANT** LIST OF REFERENCES CITED BY APPLICANT Hiroki SHIOMI, et al. **FILING DATE GROUP** 3618 March 1, 2002 **U.S. PATENT DOCUMENTS FILING DATE DOCUMENT** SUB EXAMINER DATE CLASS NAME IF APPROPRIATE INITIAL NUMBER **CLASS** 4,558,612 12/17/85 T. SHIMIZU, et al. AA AB 6,190,284 L 1 02/20/2001 S. KURODA, et al.  $\varepsilon_{c}$ AC 6,256,568 L 07/03/2001 A. SIEPKER, et al. AD 6,321,530 4-11/27/2001 K. HOSHI, et al. ΑE 6,371,889 4 04/16/2002 S. KURODA, et al. AF AG AΗ ΑI ΑJ ΑK AL AM ΑN **FOREIGN PATENT DOCUMENTS TRANSLATION DOCUMENT** DATE COUNTRY NUMBER NO AO AP AQ AR AS ΑT ΑU ΑV OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.) AW AX AY Additional References sheet(s) attached Examiner ERIC CULBRETH **Date Considered** \*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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